MINTEM SCHOOL 3rd-7th November 2014 University Lille 1

9.00	Monday	Tuesday	Wednesday	Thursday	Friday
	Welcome	Imaging,	Diffraction	HRTEM G1/G2	Imaging defects
10.00	Sample Prep	perfect crystal	SAED, PED	C. Ferraris CM30	P. Cordier, Tecnai
	and	P. Cordier, Tecnai	Kikuchi, CBED		
11.00	microscope	EDX/STEM		EELS G1/G2	Defects
	presentation			N. Miyajima, A. Mussi	
12.00	A. Mussi	H. Leroux, Tecnai	D. Jacob, Tecnai	Tecnai	P. Cordier
	lunch	lunch	lunch	lunch	lunch
13.30					
	TEM	Image/Amplitude	Crystallography	Phase contrast	Debriefing
	Ray Path	(perfect crystal)	Spot patt. Indexing		Evaluation
15.00	D. Jacob	P. Cordier	D. Jacob	C. Ferraris	
15.30					
	e-/solid	EDX/STEM	Spot Patterns, PED	EELS	
17.00	H. Leroux	H. Leroux	D. Jacob	N. Miyajima	

TEM session lecture/practical